Absolute Maximum Ratings

Absolute maximum ratings indicate sustained limits beyond which damage to the device may occur. All voltage parameters are absolute voltages referenced to COM. The thermal resistance and power dissipation ratings are measured under board mounted and still air conditions.

Symbol	Definition		Min.	Max.	Units
V_B	High side floating supply voltage		-0.3	225	V
V_S	High side floating supply offset voltage		V_B - 25	V_B + 0.3	
V_{HO}	High side floating output voltage		V_S - 0.3	V_B + 0.3	
V_{CC}	Low side fixed supply voltage		-0.3	25	
V_{LO}	Low side output voltage		-0.3	V_{CC} +0.3	
V_{IN}	Logic input voltage (HIN & LIN)		-0.3	V_{CC} +0.3	
dV_S/dt	Allowable offset supply voltage transient (figure 2)		—	50	V/ns
P_D	Package power dissipation @ $T_A \leq +25°C$	(8-lead DIP)	—	1.0	W
		(8-lead SOIC)	—	0.625	
R_{THJA}	Thermal resistance, junction to ambient	(8-lead DIP)	—	125	°C/W
		(8-lead SOIC)	—	200	
T_J	Junction temperature		—	150	°C
T_S	Storage temperature		-55	150	
T_L	Lead temperature (soldering, 10 seconds)		—	300	

Recommended Operating Conditions

For proper operation the device should be used within the recommended conditions. The V_S and COM offset ratings are tested with all supplies biased at 15V differential.

Symbol	Definition	Min.	Max.	Units
V_B	High side floating supply absolute voltage	V_S + 10	V_S + 20	V
V_S	High side floating supply offset voltage	Note 1	200	
V_{HO}	High side floating output voltage	V_S	V_B	
V_{CC}	Low side fixed supply voltage	10	20	
V_{LO}	Low side output voltage	0	V_{CC}	
V_{IN}	Logic input voltage (HIN & LIN)	COM	5.5	
T_A	Ambient temperature	-40	125	

Note 1: Logic operational for V_S of -4 to +200V. Logic state held for V_S of -4V to $-V_{BS}$.

Dynamic Electrical Characteristics

V_{BIAS} (V_{CC}, V_{BS}) = 15V, C_L = 1000 pF, T_A = 25°C unless otherwise specified. Figure 1 shows the timing definitions.

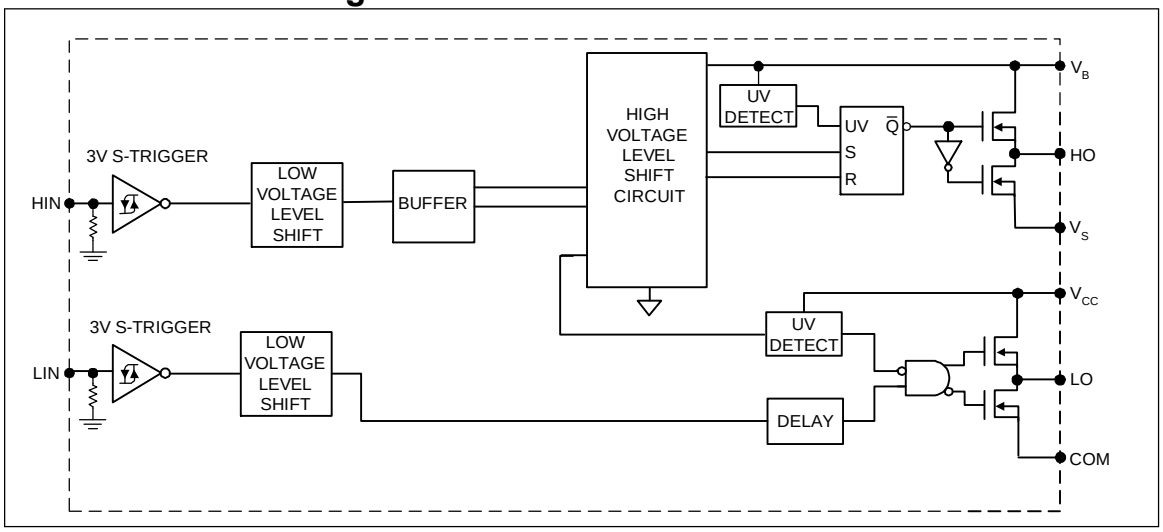
Symbol	Definition	Min.	Typ.	Max.	Units	Test Conditions
t_{on}	Turn-on propagation delay	—	80	—	ns	V_S = 0V
t_{off}	Turn-off propagation delay	—	75	—		V_S = 200V
t_r	Turn-on rise time	—	35	50		
t_f	Turn-off fall time	—	20	35		
DM1	Turn-on delay matching | t_{on} (H) - t_{on} (L) |	—	—	20		
DM2	Turn-off delay matching | t_{off} (H) - t_{off} (L) |	—	—	20		

Static Electrical Characteristics

V_{BIAS} (V_{CC}, V_{BS}) = 15V, and T_A = 25°C unless otherwise specified. The V_{IN}, V_{TH} and I_{IN} parameters are referenced to COM and are applicable to all logic input leads: HIN and LIN. The V_O and I_O parameters are referenced to COM and are applicable to the respective output leads: HO or LO.

Symbol	Definition	Min.	Typ.	Max.	Units	Test Conditions
V_{IH}	Logic “1” input voltage	2.2	—	—	V	V_{CC} = 10V - 20V
V_{IL}	Logic “0” input voltage	—	—	0.7		
V_{OH}	High level output voltage, V_{BIAS} - V_O	—	—	2.0		I_O = 0A
V_{OL}	Low level output voltage, V_O	—	—	0.2		20mA
I_{LK}	Offset supply leakage current	—	—	50	µA	V_B=V_S = 200V
I_{QBS}	Quiescent V_{BS} supply current	—	90	210		V_{IN} = 0V or 3.3V
I_{QCC}	Quiescent V_{CC} supply current	—	140	230		V_{IN} = 0V or 3.3V
I_{IN+}	Logic “1” input bias current	—	7.0	20		V_{IN} = 3.3V
I_{IN-}	Logic “0” input bias current	—	—	1.0		V_{IN} = 0V
V_{BSUV+}	V_{BS} supply undervoltage positive going threshold	8.2	9.0	9.8	V	
V_{BSUV-}	V_{BS} supply undervoltage negative going threshold	7.4	8.2	9.0		
V_{CCUV+}	V_{CC} supply undervoltage positive going threshold	8.2	9.0	9.8		
V_{CCUV-}	V_{CC} supply undervoltage negative going threshold	7.4	8.2	9.0		
I_{O+}	Output high short circuit pulsed current	—	1.0	—	A	V_O = 0V, PW ≤ 10 µs
I_{O-}	Output low short circuit pulsed current	—	1.0	—		V_O = 15V, PW ≤ 10 µs

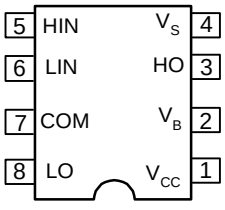
Functional Block Diagram



Lead Definitions

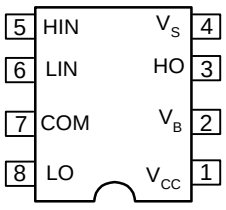
Symbol	Description
HIN	Logic input for high side gate driver output (HO), in phase
LIN	Logic input for low side gate driver output (LO), in phase
V_B	High side floating supply
HO	High side gate drive output
V_S	High side floating supply return
V_{CC}	Low side supply
LO	Low side gate drive output
COM	Low side return

Lead Assignments



8-Lead PDIP

IR2011



8-Lead SOIC

IR2011S

Part Number

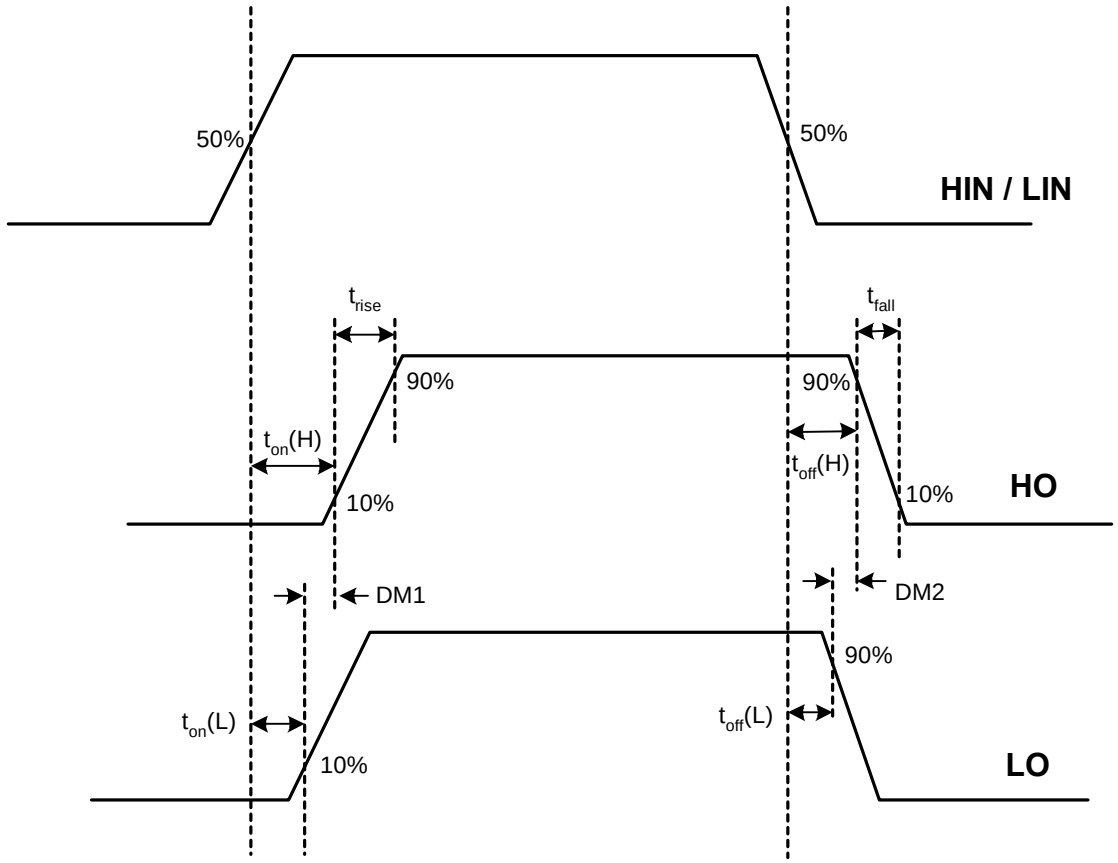


Figure 1. Timing Diagram

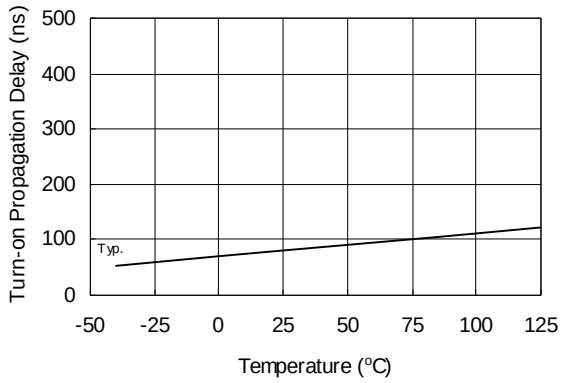


Figure 2A. Turn-on Propagation Delay vs. Temperature

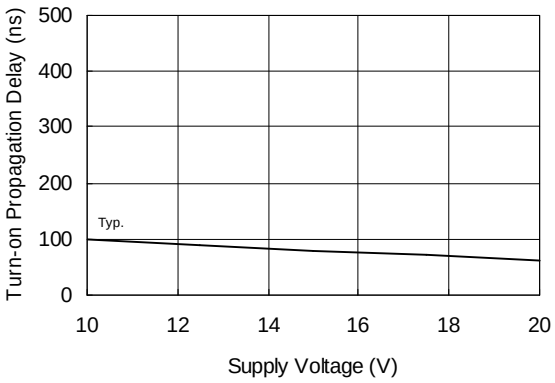


Figure 2B. Turn-on Propagation Delay vs. Supply Voltage

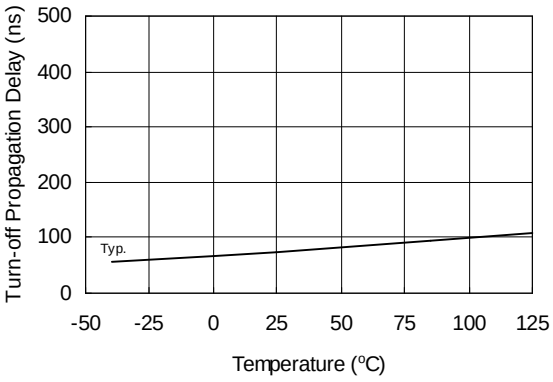


Figure 3A. Turn-off Propagation Delay vs. Temperature

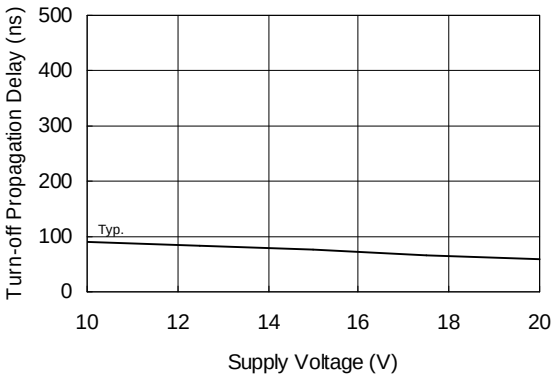


Figure 3B. Turn-off Propagation Delay vs. Supply Voltage

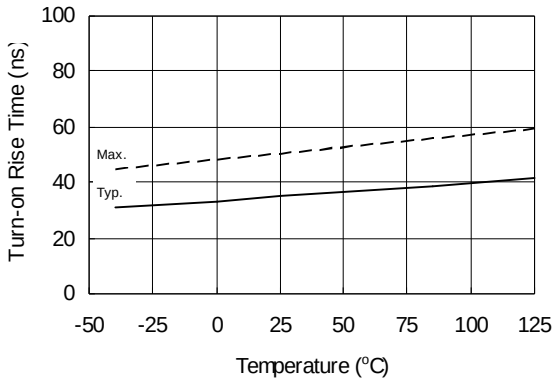


Figure 4A. Turn-on Rise Time vs. Temperature

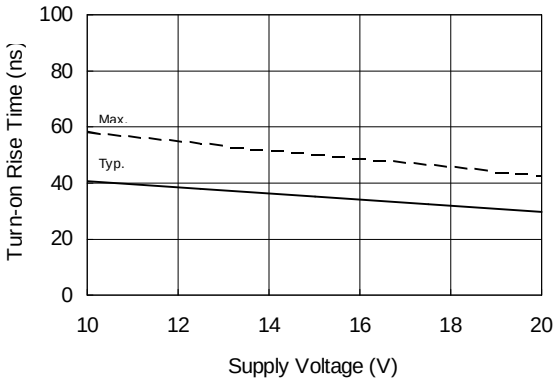


Figure 4B. Turn-on Rise Time vs. Supply Voltage

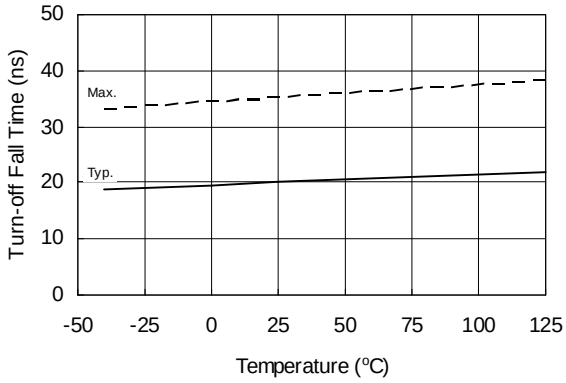


Figure 5A. Turn-off Fall Time vs. Temperature

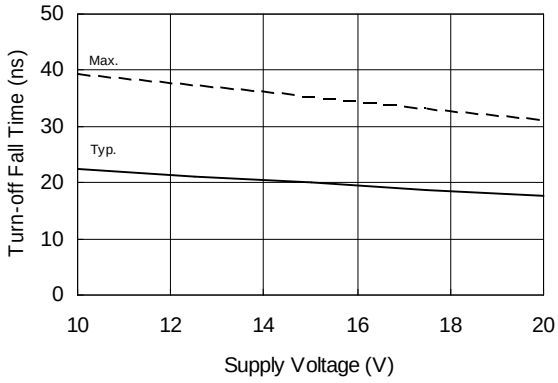


Figure 5B. Turn-off Fall Time vs. Supply Voltage

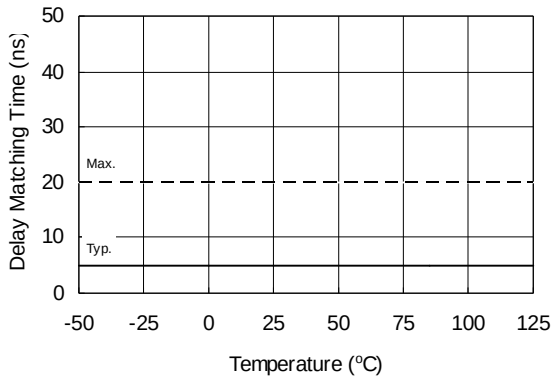


Figure 6A. Turn-on Delay Matching Time vs. Temperature

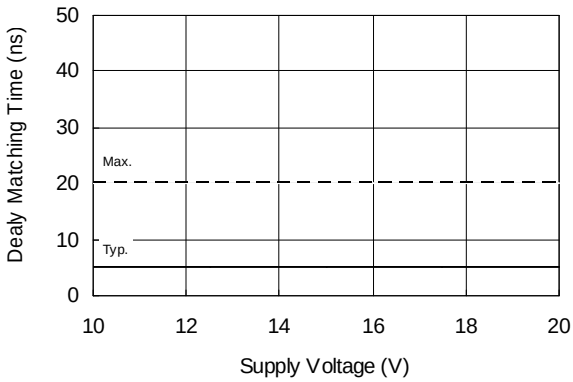


Figure 6B. Turn-on Delay Matching Time vs. Supply Voltage

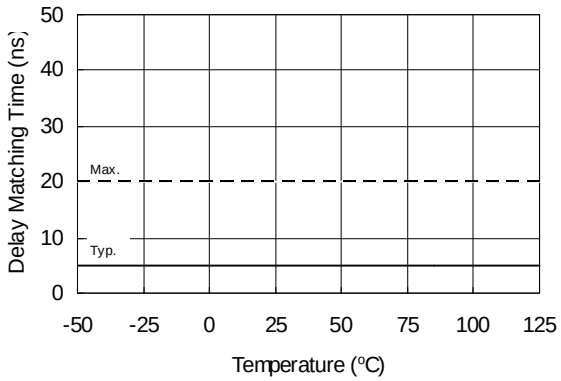


Figure 7A. Turn-off Delay Matching Time vs. Temperature

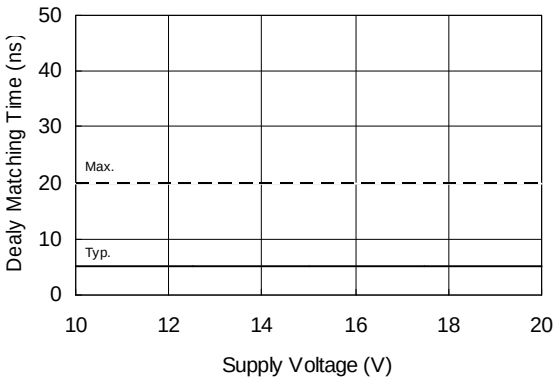


Figure 7B. Turn-off Delay Matching Time vs. Supply Voltage

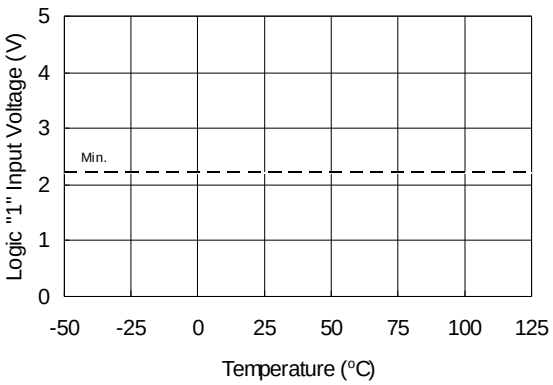


Figure 8A. Logic "1" Input Voltage vs. Temperature

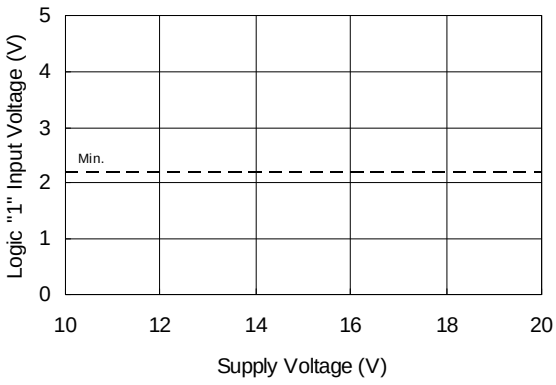


Figure 8B. Logic "1" Input Voltage vs. Supply Voltage

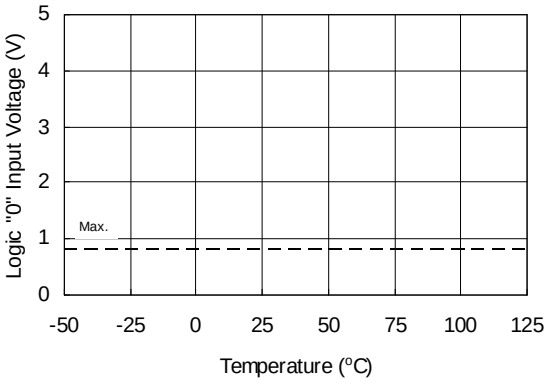


Figure 9A. Logic "0" Input Voltage vs. Temperature

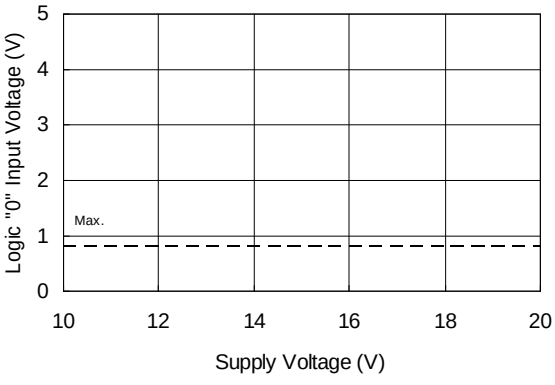


Figure 9B. Logic "0" Input Voltage vs. Supply Voltage

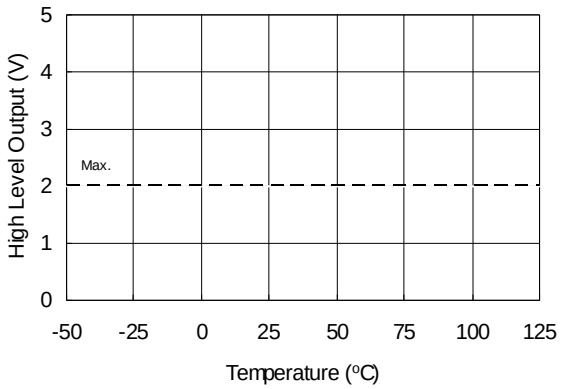


Figure 10A. High Level Output vs.Temperature

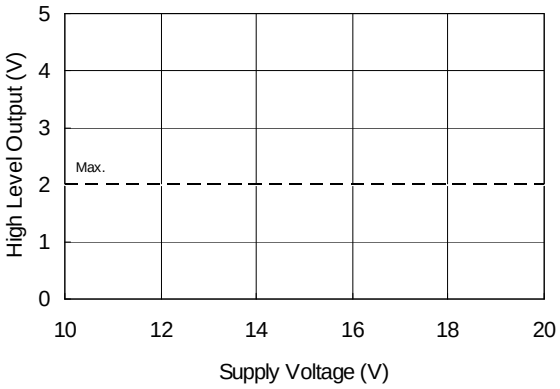


Figure 10B. High Level Output vs. Supply Voltage

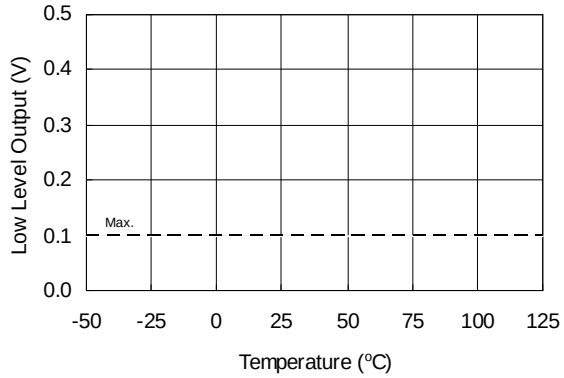


Figure 11A. Low Level Output vs. Temperature

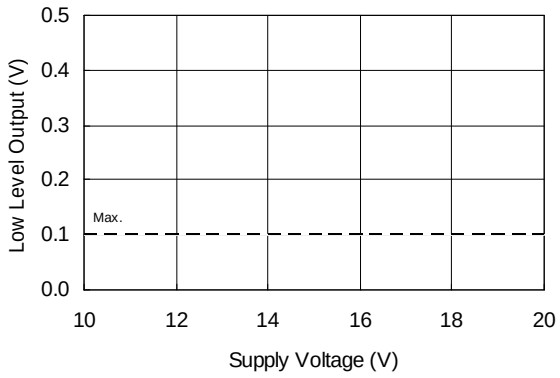


Figure 11B. Low Level Output vs. Supply Voltage

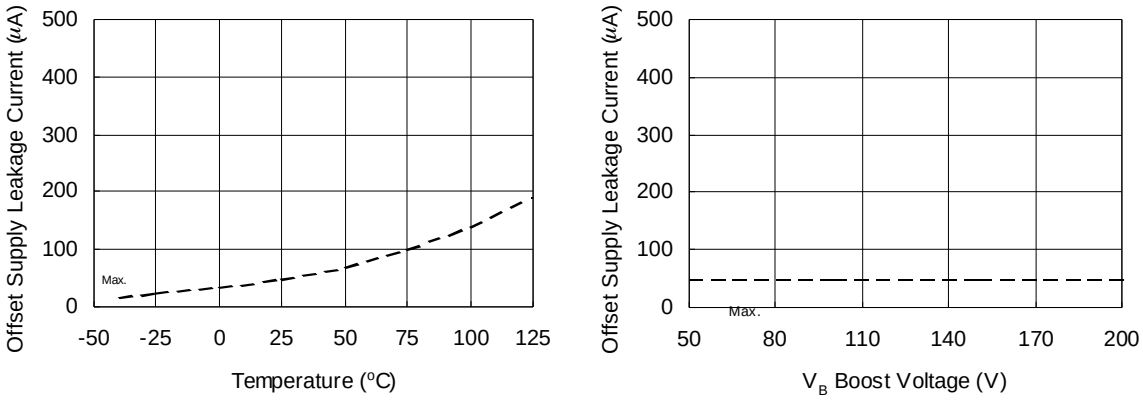
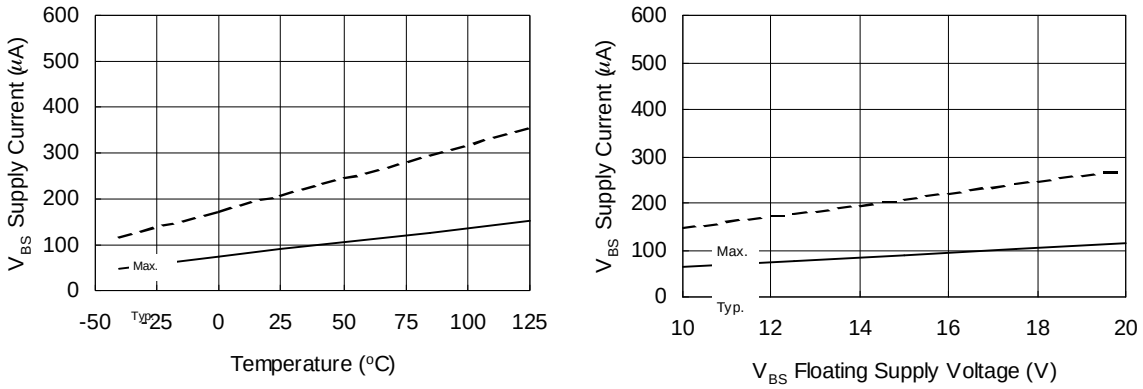


Figure 12A. Offset Supply Leakage Current vs. Temperature



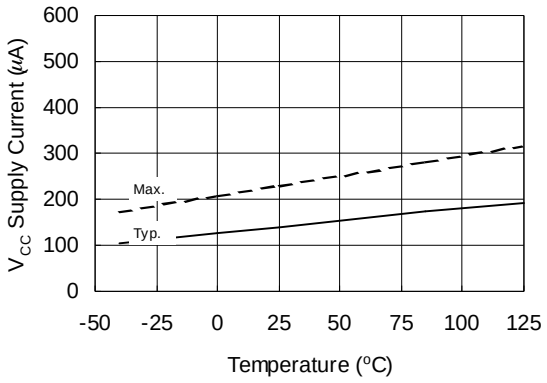


Figure 14A. V_{CC} Supply Current vs. Temperature

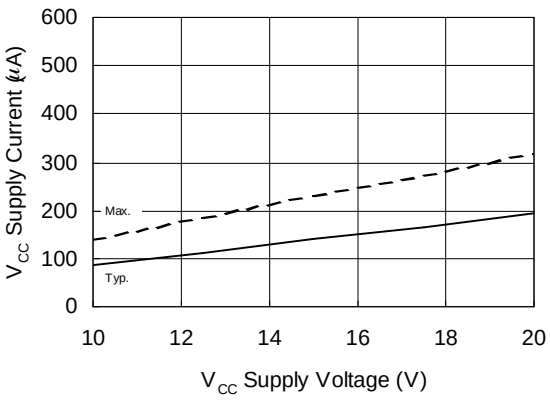


Figure 14B. V_{CC} Supply Current vs. V_{CC} Supply Voltage

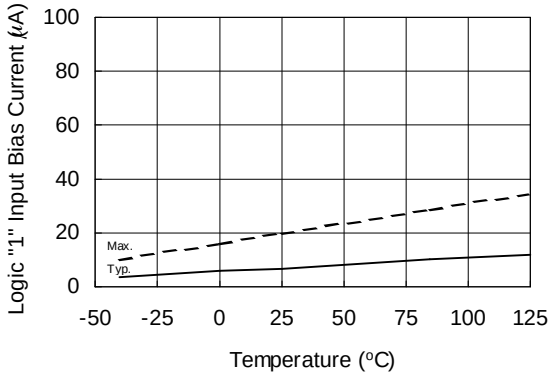
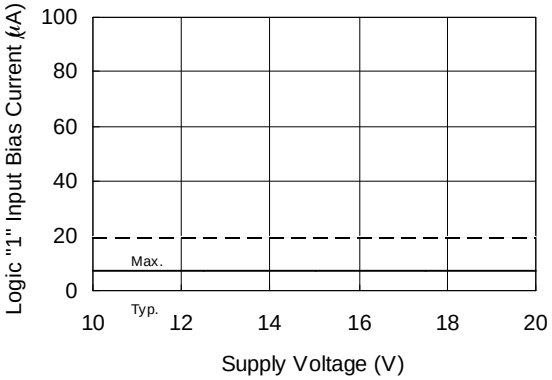


Figure 15A. Logic "1" Input Bias Current vs. Temperature



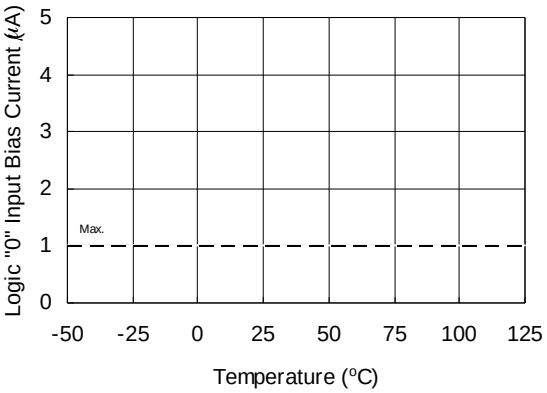


Figure 16A. Logic "0" Input Bias Current vs. Temperature

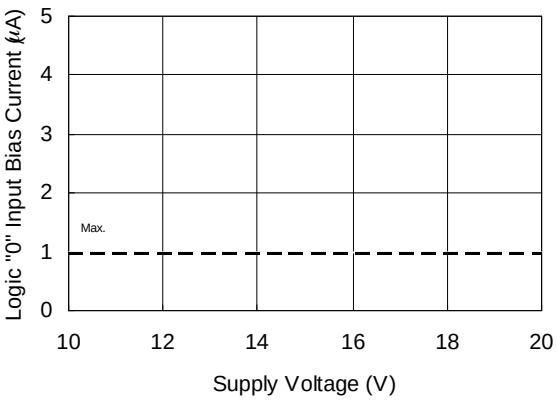


Figure 16B. Logic "0" Input Bias Current vs. Supply Voltage

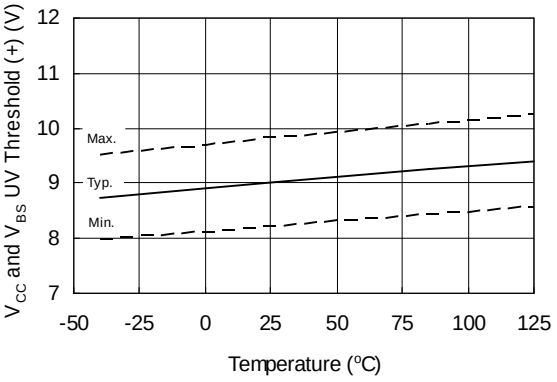


Figure 17. V_{CC} and V_{BS} Undervoltage Threshold (+) vs. Temperature

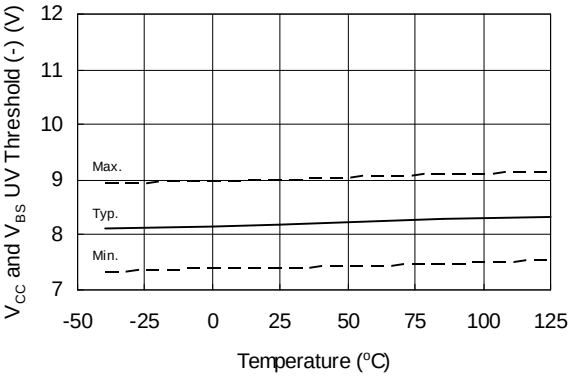


Figure 18. V_{CC} and V_{BS} Undervoltage Threshold (-) vs. Temperature

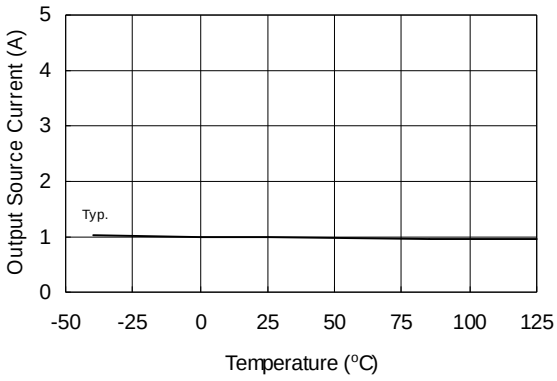


Figure19A. Output Source Current vs. Temperature

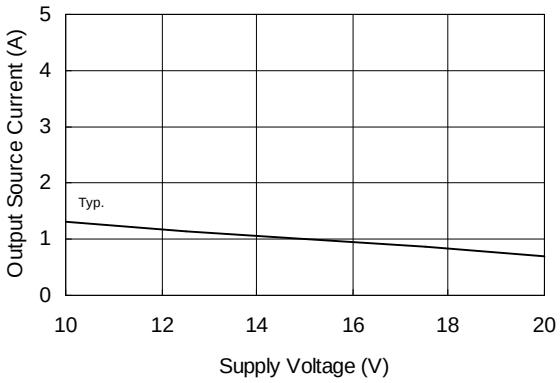


Figure 19B. Output Source Current vs. Supply Voltage

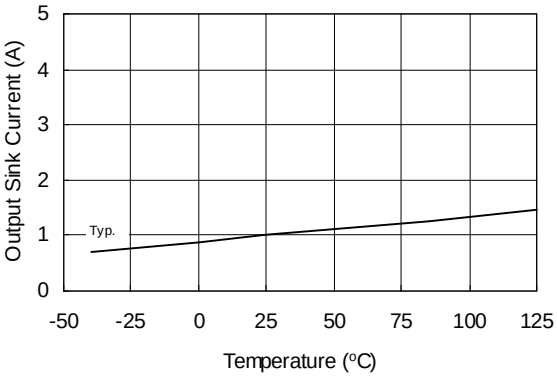


Figure 20A. Output Sink Current vs. Temperature

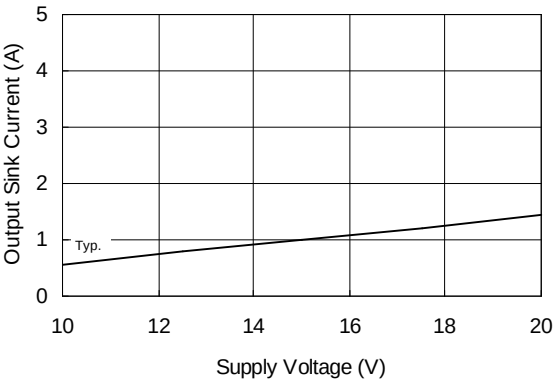


Figure 20B. Output Sink Current vs. Supply Voltage

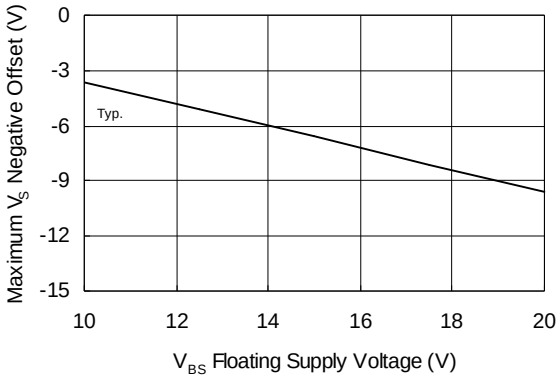
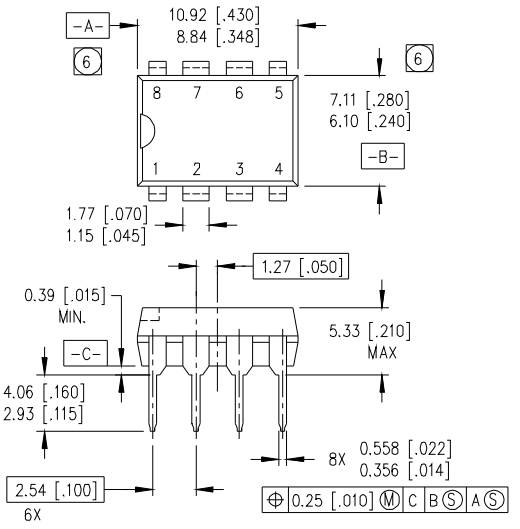
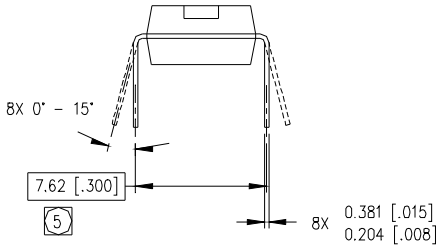


Figure 21. Maximum V_S Negative Offset vs. V_{BS} Floating Supply Voltage

Case outlines

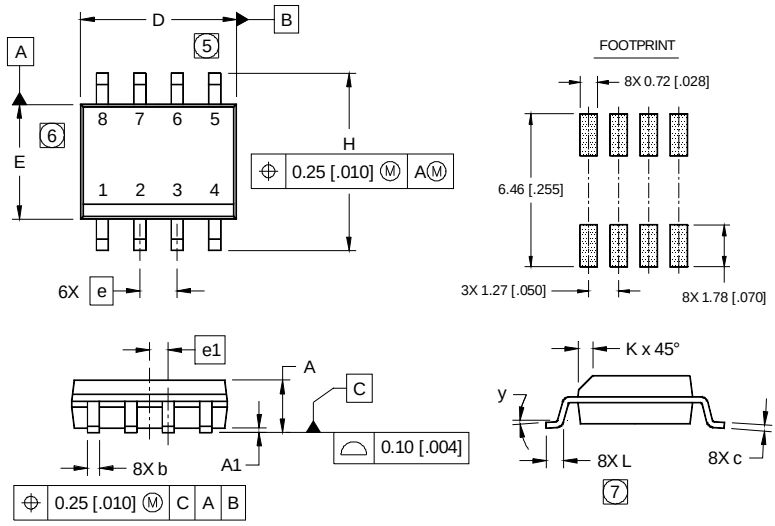


NOTES:
1. DIMENSIONING & TOLERANCING PER ANSI Y14.5M-1982.
2. CONTROLLING DIMENSION: INCH.
3. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].
4. OUTLINE CONFORMS TO JEDEC OUTLINE MS-001AB.
5. MEASURED WITH THE LEADS CONSTRAINED TO BE PERPENDICULAR TO DATUM PLANE C.
6. DIMENSION DOES NOT INCLUDE MOLD PROTUSIONS. MOLD PROTUSIONS SHALL NOT EXCEED 0.25 [.010].



8-Lead PDIP

01-6014
01-3003 01 (MS-001AB)



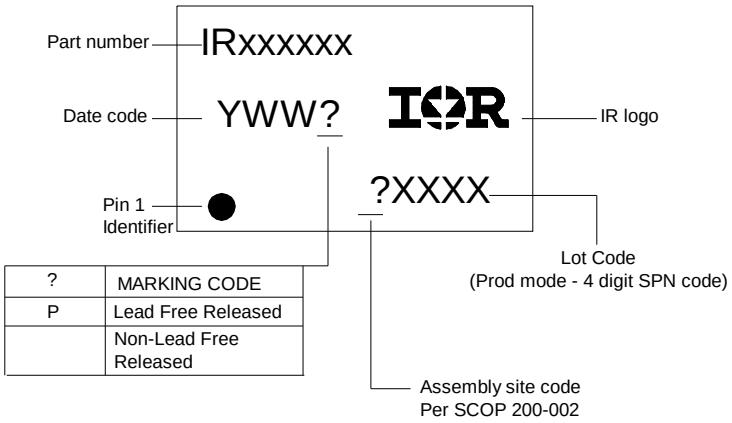
DIM	INCHES		MILLIMETERS	
	MIN	MAX	MIN	MAX
A	.0532	.0688	1.35	1.75
A1	.0040	.0098	0.10	0.25
b	.013	.020	0.33	0.51
c	.0075	.0098	0.19	0.25
D	.189	.1968	4.80	5.00
E	.1497	.1574	3.80	4.00
e	.050 BASIC		1.27 BASIC	
e 1	.025 BASIC		0.635 BASIC	
H	.2284	.2440	5.80	6.20
K	.0099	.0196	0.25	0.50
L	.016	.050	0.40	1.27
y	0°	8°	0°	8°

NOTES:
1. DIMENSIONING & TOLERANCING PER ASME Y14.5M-1994.
2. CONTROLLING DIMENSION: MILLIMETER
3. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].
4. OUTLINE CONFORMS TO JEDEC OUTLINE MS-012AA.
5. DIMENSION DOES NOT INCLUDE MOLD PROTRUSIONS. MOLD PROTRUSIONS NOT TO EXCEED 0.15 [.006].
6. DIMENSION DOES NOT INCLUDE MOLD PROTRUSIONS. MOLD PROTRUSIONS NOT TO EXCEED 0.25 [.010].
7. DIMENSION IS THE LENGTH OF LEAD FOR SOLDERING TO A SUBSTRATE.

8-Lead SOIC

01-6027
01-0021 11 (MS-012AA)

LEADFREE PART MARKING INFORMATION



?	MARKING CODE
P	Lead Free Released
	Non-Lead Free Released

ORDER INFORMATION

Basic Part (Non-Lead Free)
8-Lead PDIP IR2011 order IR2011
8-Lead SOIC IR2011S order IR2011S

Leadfree Part
8-Lead PDIP IR2011 order IR2011PbF
8-Lead SOIC IR2011S order IR2011SPbF

This product has been designed and qualified for the industrial market.
Qualification Standards can be found on IR's Web Site *http://www.irf.com/.*
Data and specifications subject to change without notice
WORLD HEADQUARTERS: 233 Kansas Street, El Segundo, California 90245 Tel: (310) 252-7105
3/4/2008